

STY112N65M5

N-channel 650 V, 0.019 Ω 96 A, MDmesh™ V Power MOSFET Max247

Features

Order code	V _{DSS} @T _{jMAX}	R _{DS(on)} max	I _D
STY112N65M5	710 V	< 0.022 Ω	96 A

- Max247 worldwide best R_{DS(on)}
- Higher V_{DSS} rating
- Higher dv/dt capability
- Excellent switching performance
- Easy to drive
- 100% avalanche tested



Switching applications

Description

The device is an N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

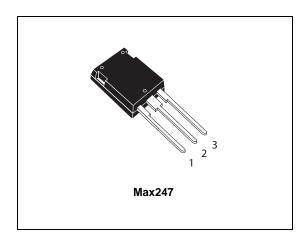


Figure 1. Internal schematic diagram

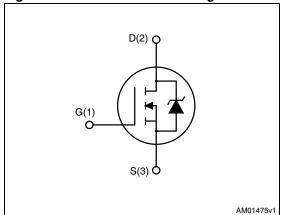


Table 1. Device summary

Order code	Marking	Package	Packaging
STY112N65M5	112N65M5	Max247	Tube

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STY112N65M5 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V _{GS}	Gate- source voltage	25	V	
I _D	Drain current (continuous) at T _C = 25 °C 96			
I _D	Drain current (continuous) at T _C = 100 °C 61			
I _{DM} ⁽¹⁾	Drain current (pulsed)	384	Α	
P _{TOT}	Total dissipation at T _C = 25 °C	625	W	
I _{AR}	Max current during repetitive or single pulse avalanche (pulse width limited by T _{JMAX})		А	
E _{AS}	Single pulse avalanche energy (starting $T_j = 25^{\circ}\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{V}$)		mJ	
dv/dt ⁽²⁾	Peak diode recovery voltage slope 15		V/ns	
T _{stg}	Storage temperature - 55 to 150		°C	
T _j	Max. operating junction temperature	150	°C	

^{1.} Pulse width limited by safe operating area.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	0.2	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	30	°C/W
T _I	Maximum lead temperature for soldering purpose	300	°C

^{2.} $I_{SD} \leq 96 \text{ A, di/dt} = 400 \text{ A/µs, } V_{DD} = 400 \text{ V, peak } V_{DS} < V_{(BR)DSS}$.

Electrical characteristics STY112N65M5

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 1 mA, V _{GS} = 0	650			٧
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating, T_{C} =125 °C			1 100	μA μA
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10 V, I _D = 48 A		0.019	0.022	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 100 \text{ V, } f = 1 \text{ MHz,}$ $V_{GS} = 0$		16870 365 7		pF pF pF
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	$V_{GS} = 0$, $V_{DS} = 0$ to 520 V		1333		pF
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related	$V_{GS} = 0$, $V_{DS} = 0$ to 520 V		350		pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain		1.26		Ω
Q_g	Total gate charge	$V_{DD} = 520 \text{ V}, I_{D} = 48 \text{ A},$		350		nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V		97		nC
Q_{gd}	Gate-drain charge	(see Figure 15)		118		nC

C_{o(tr)} is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

^{2.} $C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(v)}	Voltage delay time	V _{DD} = 400 V, I _D = 64 A,		267		ns
t _{r(v)}	Voltage rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$		79		ns
t _{f(i)}	Current fall time	(see Figure 16)	_	53	-	ns
t _{c(off)}	Crossing time	(see Figure 19)		140		ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		96 384	A A
V _{SD} (2)	Forward on voltage	I _{SD} = 96 A, V _{GS} = 0	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 96 A, di/dt = 100 A/μs V _{DD} = 100 V (see <i>Figure 16</i>)	-	570 17 60		ns µC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 96$ A, di/dt = 100 A/ μ s $V_{DD} = 100$ V, $T_j = 150$ °C (see <i>Figure 16</i>)	-	695 26 73		ns µC A

^{1.} Pulse width limited by safe operating area

^{2.} Pulsed: pulse duration = $300 \mu s$, duty cycle 1.5%

Electrical characteristics STY112N65M5

2.1 Electrical characteristics (curves)

100

Figure 2. Safe operating area

(A)

100

10

0.1

BVDSS (norm)

1.07

1.051.03

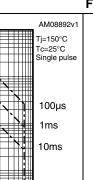
1.01

0.99

0.95

0.93 -50 -25

0 25



V_Ds(V)

Figure 3. Thermal impedance

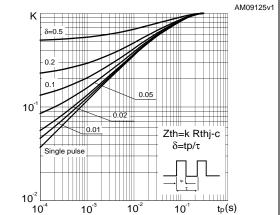


Figure 4. Output characteristics

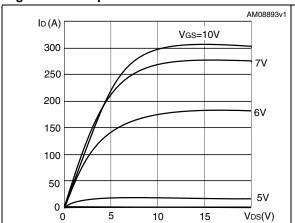


Figure 5. Transfer characteristics

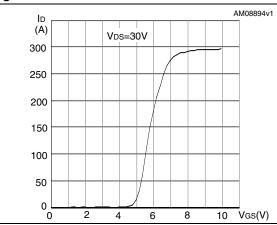


Figure 6. Normalized B_{VDSS} vs temperature

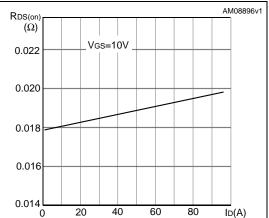
ID=1mA

75

50



Figure 7. Static drain-source on resistance



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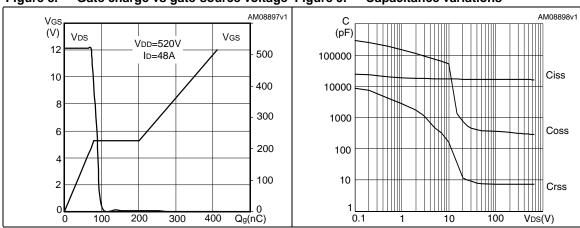


Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

Figure 10. Normalized gate threshold voltage Figure 11. Normalized on resistance vs vs temperature temperature

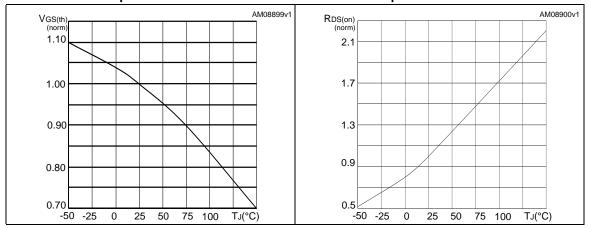
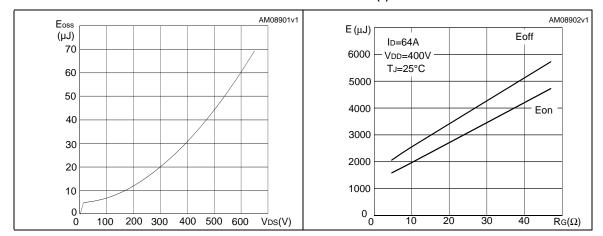


Figure 12. Output capacitance stored energy Figure 13. Switching losses vs gate resistance



1. Eon including reverse recovery of a SiC diode

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Test circuits STY112N65M5

3 Test circuits

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

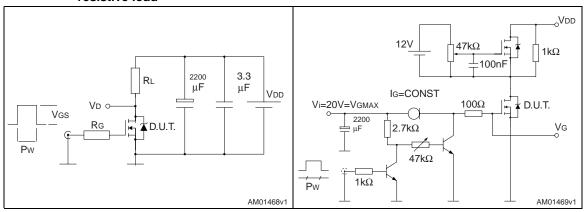


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped inductive load test circuit

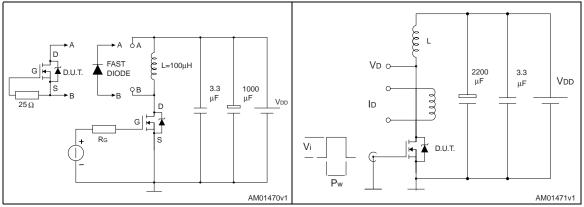
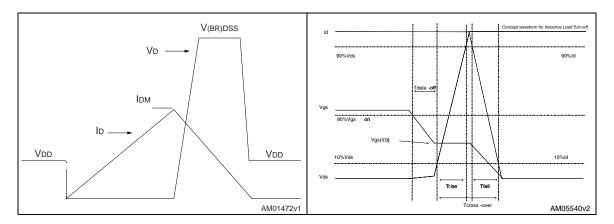


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



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4 Package mechanical data

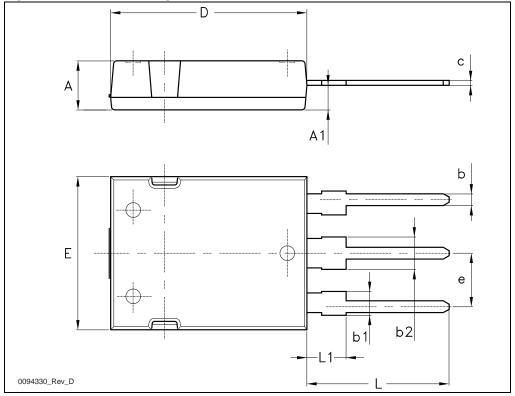
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Table 8. Max247 mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
А	4.70		5.30
A1	2.20		2.60
b	1.00		1.40
b1	2.00		2.40
b2	3.00		3.40
С	0.40		0.80
D	19.70		20.30
е	5.35		5.55
E	15.30		15.90
L	14.20		15.20
L1	3.70		4.30

Figure 20. Max247 drawing



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STY112N65M5 Revision history

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
20-Jan-2009	1	First release.
20-May-2011	2	Document status pomoted from preliminary data to datasheet.

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